

Application/Control No.		Applicant(s)/Patent under Reexamination	
	10/633,105	HAN ET AL.	
Γ	Examiner	Art Unit	_
	Mark Blouin	2627	

	SEARCHED				
Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
360	126	6/2/16	%		
29	603	6/7/06	v~3		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
Swich (loss 360,29 See EAST Liby		VV)			
Text Scarded 36929 See EAST 16 kg	6/7/06	vs			